

**Search Notes**

Application/Control No.

10/048,164

Examiner

Matthew Heneghan

Applicant(s)/Patent under  
Reexamination

KURIYA ET AL.

Art Unit

2134

**SEARCHED**

Class	Subclass	Date	Examiner
726	29	5/2/2007	MH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
PGPUB Interference Search		5/2/2007	MH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STIC Fast & Focused Search, see notes	4/23/2007	MH
EAST Update Search, see notes	5/2/2007	MH
ACM, IEEE Searches	5/2/2007	MH
Inventor Search	5/2/2007	MH